

Supporting Information

Anti-counterfeit nanoscale fingerprints based on randomly distributed nanowires

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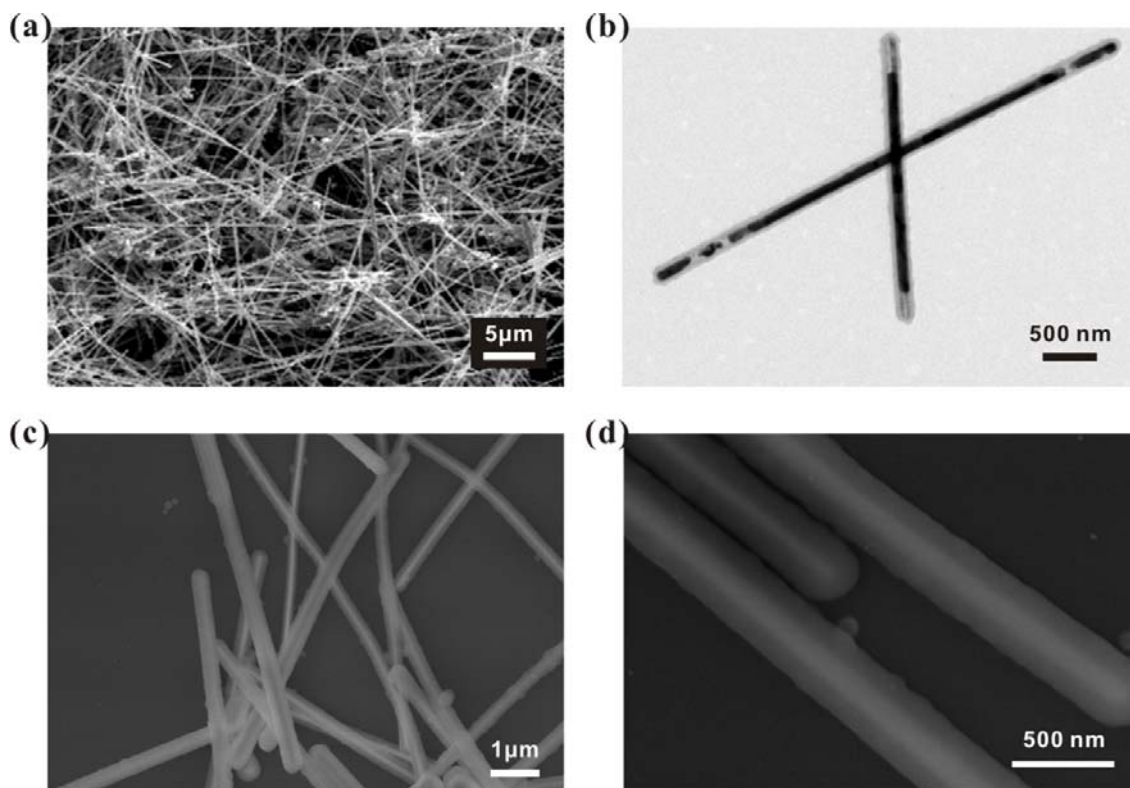


Figure S1. (a) SEM image of AgNWs with an average diameter of 70 ± 6 nm (scale bar = 5 μ m). (b) TEM image of the core-shell AgNWs@amorphous silica with a diameter of ca. 212 ± 16 nm shown in Figure 2. (c), (d) SEM image of the core shell AgNWs@amorphous silica with an average diameter of 392 ± 26 nm shown in Figure 2(c).

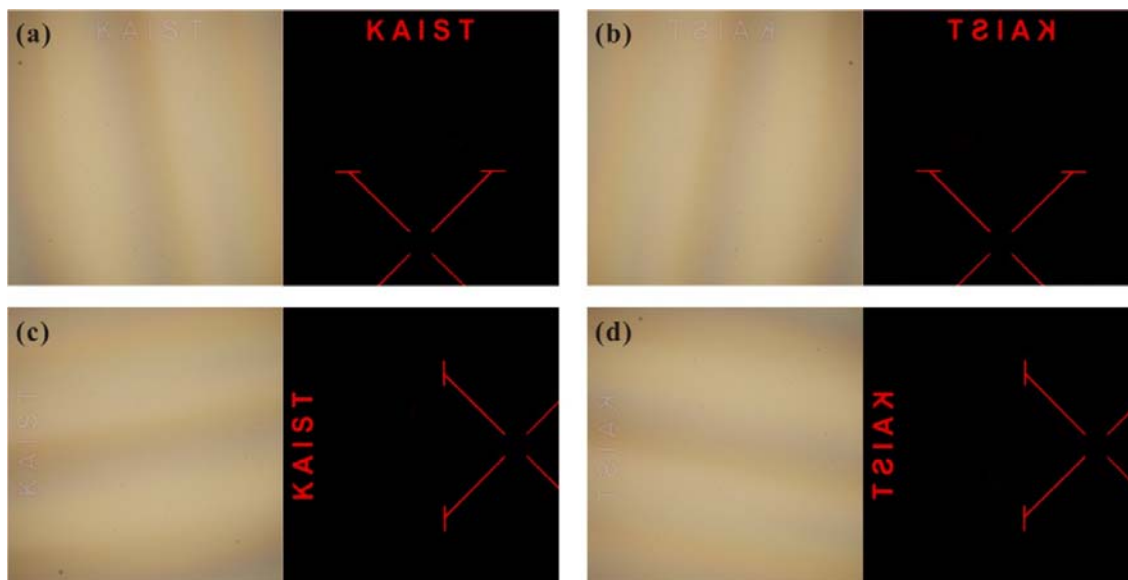


Figure S2. Various orientations of the substrate can be easily identified by the orientation marker (KAIST). Optical (left) and fluorescence (right) microscope images are shown for (a) the correct orientation, (b) flipped orientation, (c) anti-clockwise 90° rotation, and (d) anti-clockwise 90° rotation and flipped orientation.